


<b>Search Notes</b>  	<b>Application/Control No.</b>  10663714	<b>Applicant(s)/Patent Under Reexamination</b>  INOUE ET AL.
	<b>Examiner</b>  Ahmed Sefer	<b>Art Unit</b>  2826

SEARCHED			
Class	Subclass	Date	Examiner
257	103,744,745,98	6/12/08	A.S.
438	25,27	6/12/08	A.S.

SEARCH NOTES		
Search Notes	Date	Examiner
EAST (USPAT, US-PG-Pub, Derwent, EPO & JPO)	6/12/08	A.S.
257/E33.005 257/E33.028 257/E33.064	6/12/08	A.S.

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner